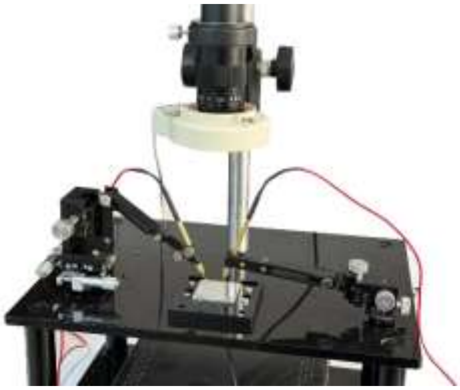
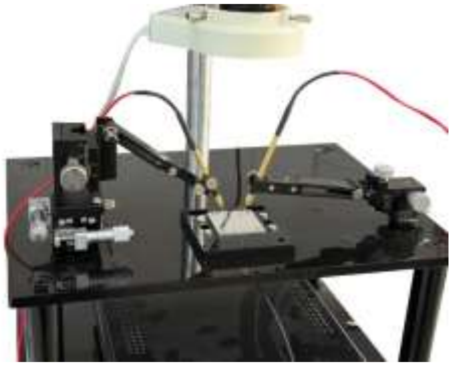
TRONIX

Providing Modern Electrical Solutions

THIN FILM TRANSISTOR CHARACTERIZATION SYSTEM





The system is a complete THIN FILM TRANSISTOR CHARACTERIZATION system.

Technical Datasheet

The system contains the following elements:

Sourcemeter

Probe station

Voltage range: -200 V to +200 V

Current range: 10Pa-1A

Software

PROBE STATION can be used for current-voltage characteristics of electronic devices such as solar cell, photodiode, sensor and thin film transıstors. Probe station is designed according to below technical properties

XYZ manipulators (2 or 3)

Vacuum chuck
Temperature chuck
Temperature controller

Microscope for thin film transistor applications
High resolution camera: 5 MPA
Magnification: 130X
Monitor

Probe pin: Spring pin